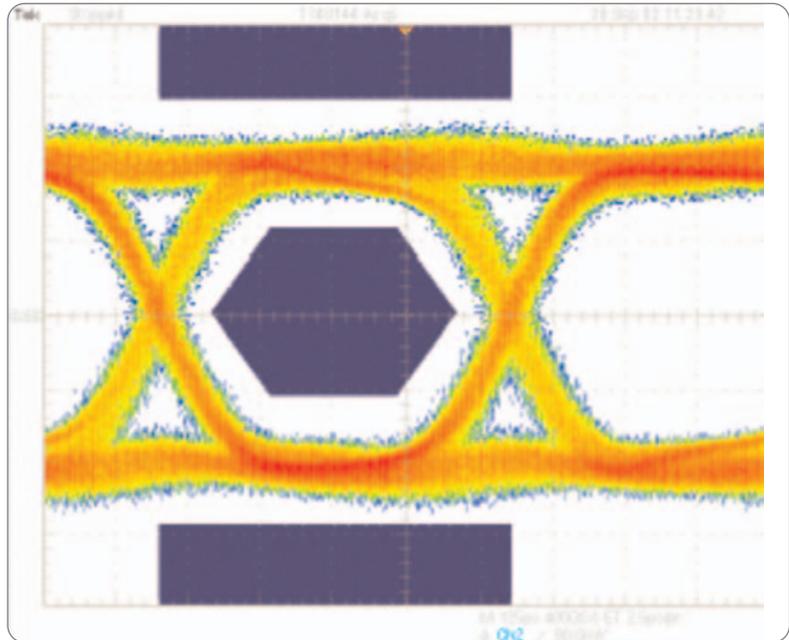


# Understanding Digital Video Interface (DVI) Compliance Testing



- **Engineers involved in design, characterization and validation of DVI devices face daily pressure to speed new products to marketplace. The challenge for these designers is to have their devices be inter-operable with a huge set of DVI devices from other companies, already available in the market place. Successfully validating their designs to the DVI specification by performing compliance testing ensures the designer of a robust design.**

Digital Visual Interface (DVI) is a display interface that supports data transfer from a PC to a flat panel display in digital format. Used extensively in the PC market, DVI eliminates the need to convert this digital data into analog data for transmission, improving performance and video quality.

The DVI specification and the DVI Test and Measurement Guide introduce new testing requirements. As a DVI device designer you must properly characterize designs and verify compliance to ensure inter-operability among other DVI devices. This is necessary for a pleasant user experience.

An appropriate tool set is critical for performing DVI physical layer tests as specified by the DVI Test and Measurement Guide.

This application note will focus on understanding and performing physical layer measurements.

# Understanding Digital Video Interface (DVI) Compliance Testing

## ► Application Note

### DVI Basics

DVI uses a high-speed serial interface that uses transition minimized differential signaling (TMDS) to send data to the monitor. TMDS conveys data by transitioning between “on” and “off” states. An advanced encoding algorithm that uses Boolean exclusive OR (XOR) or exclusive NOR (XNOR) operations is applied to minimize the transitions. Minimizing transitions avoids excessive electromagnetic interference (EMI) levels on the cable. An additional operation is performed to balance the DC signal.

Figure 1 shows the flow of display (or pixel) data from the graphics controller through TMDS mechanisms (implemented in a chip on the graphics card or in the graphics chip set) and the display controller. In this process, incoming 8-bit data is encoded into 10-bit transition-minimized, DC-balanced characters. (The first eight bits are the encoded data; the ninth bit identifies whether the data was encoded with XOR or XNOR logic; the tenth bit is used for DC balancing.)

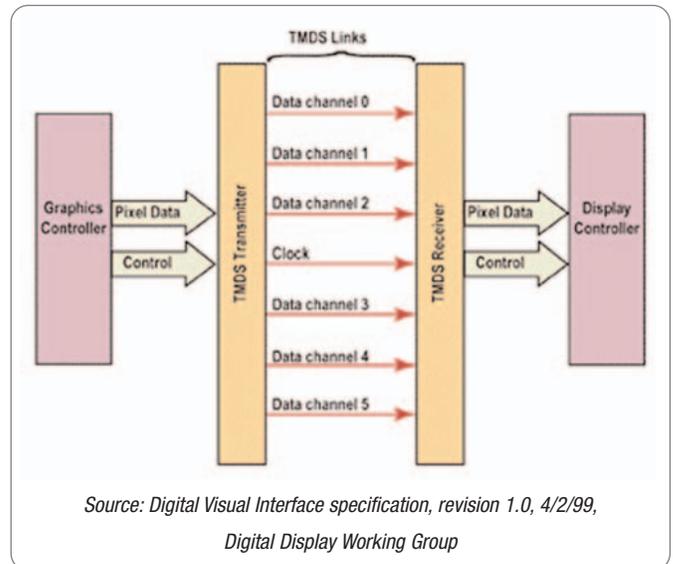
As shown in Figure 1, DVI allows for up to two TMDS links. Each link is composed of three data channels for RGB information and has a maximum bandwidth of 165 MHz, which equates to 165 million pixels per second. For a dual link implementation, this becomes 330 million pixels per second. The two links share the same clock so that bandwidth can be divided evenly between them. The system enables one or both links, depending on the capabilities of the monitor.

### Signal Speeds at PHY Layer

165 MHz is the fastest clock speed that DVI can encounter. However, data is transmitted 10 times faster than the clock. Hence, DVI can encounter data rates up to 1.65 Gbps. This translates to the fastest rise times of 75ps on the highest DVI resolutions. Current implementations have typical rise times of the order of 250 ps to 300 ps.

### Display Resolutions

Video Electronics and Electronics Association (VESA) maintains a set of standard display resolutions. Table below reviews some of the standard PC display resolutions.



► Figure 1. TMDS Logical Links.

Resolution Name	Pixel Resolution
Video Graphics Array (VGA)	640 x 480
Super VGA (SVGA)	800 x 600
Extended Graphics Array (XGA)	1024 x 768
Super XGA (SXGA)	1280 x 1024
Ultra XGA (UXGA)	1600 x 1200
High-Definition TV (HDTV)	1920 x 1080
Quad XGA (QXGA)	2048 x 1536

Many DVI devices support proprietary non-standard resolutions also. However, physical layer testing for these proprietary resolutions essentially remains similar in terms of the test methodology and the tests to be performed.

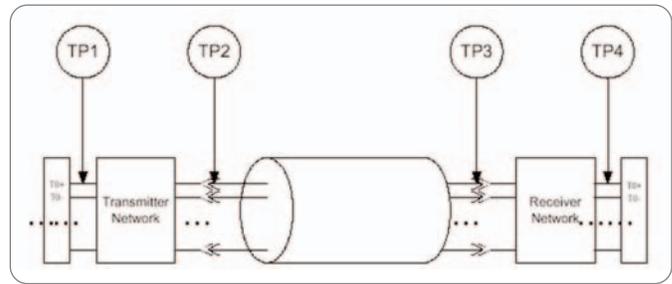
**DVI Compliance Testing**

DVI specification requires developers to comply with several stringent compliance tests for DVI designs. This is because there are hundreds of DVI devices and these devices must conform to Digital Display Working Group (DDWG) furnished specifications. This is necessary for devices to interoperate, which is essential for a satisfactory user experience and for the mass adoption of DVI technology.

Developers are required to self-comply by performing tests as per the DVI Test and Measurement Guide. This is applicable for all DVI devices.

Compliance testing is conducted for transmitter, cable and receiver at various test points as shown in the Figure 2. These test points are defined to be the contact point between the mated connected pairs of the cable assembly

Test fixture or breakout boards are required to probe the various test points (TP2 and TP3).



▶ **Figure 2.**

**DVI Electrical Tests**

**Signal Integrity Testing**

Since DVI designs can encounter typical rise times of the order of 250 ps, signal integrity testing is of paramount importance. Various tests that need to be conducted to verify signal integrity are:

- Eye diagram test
- Jitter testing
- Skew testing
- Rise time
- Fall time

**Conducting Signal Integrity Testing**

Eye diagram testing is the most critical of all the signal integrity tests. The eye diagram test provides information about jitter, amplitude and ringing effects on the signal. A pass in the eye diagram test assures a robust design.

**T<sub>bit</sub> Calculation – Essential Prerequisite to Testing**

One unit interval of the DVI signal is referred to as T<sub>bit</sub>. The DVI Test and Measurement guide recommends T<sub>bit</sub> calculation to be performed on the transmitter (differential) clock.

**Eye Diagram Test Methodology**

The DVI specification calls for guaranteeing 10<sup>-9</sup> pixel error rate. To achieve this 1 billion acquisitions on the oscilloscope is not practical. An alternate approach is to acquire less number of acquisitions and then use the statistical six-sigma method to infer a Pass or a Fail. But there are issues with the six-sigma statistical approach as it assumes the distribution to be gaussian, whereas the actual distribution is not gaussian due to systematic jitter.

Hence, the DVI test methodology, for a pseudo random pattern recommends gathering one million acquisitions to ensure simulation of worst-case jitter conditions. This is a more practical method and is recommended by the test and measurement guide as Method II.

So, after calculating the T<sub>bit</sub> and V<sub>swing</sub> is determined, both these parameters are used to construct the eye mask.

The DVI Test and Measurement Guide recommends recovering the clock (single ended) from the transmitter (differential) clock and use this recovered clock as a trigger source to the oscilloscope for testing.

**The Challenge**

Compliance testing is a challenge if it needs human intervention. The human intervention makes testing difficult and slows the test process. The DVI transmitter eye-masks (TP2) are normalized and change dynamically with the V<sub>swing</sub> and T<sub>bit</sub> values, while the cable and receiver masks (TP3) are normalized in time and change according to the changes in T<sub>bit</sub> value of the signal. This makes manual testing subjective and error prone.

Further, there are 10 data bits in one clock bit (pixel) and designers sometimes may be interested to test all the 10 data bits. In such a case, one needs to figure out the worst data bit which is essentially the data bit with the smallest T<sub>bit</sub> value amongst the 10 data bits.

# Understanding Digital Video Interface (DVI) Compliance Testing

## ► Application Note

### Test Equipment

Signal integrity testing requires a real-time oscilloscope such as the TDS7704B, TDS7404B or CSA7404B digital phosphor oscilloscopes (DPO) and differential probes such as the P7330 or P7350 probes. In addition, this testing requires automated software such as TSDSVI and a test fixture.

Figure 3, shows the TSDSVI compliance test software on a TDS7404 DPO. This test package fully automates the signal integrity test process, allowing designers to perform quick, easy and reliable tests on their designs.

A user must perform  $T_{bit}$  calculation for the device under test (DUT). Then select the measurements to be performed on a transmitter, cable or the receiver. The application must then be configured as shown in Figure 4. After completing these steps the user can run the application to get the test results.

The test software eliminates the tedium of manual, time-consuming oscilloscope set-ups, cursor placements for  $T_{bit}$  and  $V_{swing}$  calculation, and creating the mask by manually using the  $T_{bit}$  and  $V_{swing}$  values to calculate the mask coordinates and finally comparing the actual results with the DVI specification to ascertain a pass or a fail. The results are automatically displayed as illustrated in Figure 5.

Automated testing based on objective pass/fail detection without human intervention helps to achieve the time-to-market goals. The results are obtained quickly and are more reliable.

TSDSVI test software dramatically enhances productivity.

### Selecting Tools for DVI Physical Layer Testing

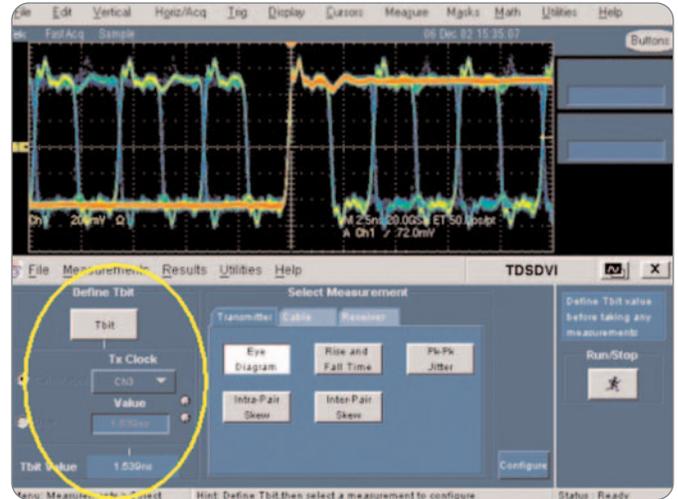
A good set of tools is the key to dependable, repeatable and reliable testing. System bandwidth and rise-time are the obvious considerations when choosing a compliance test solution.

### Oscilloscope

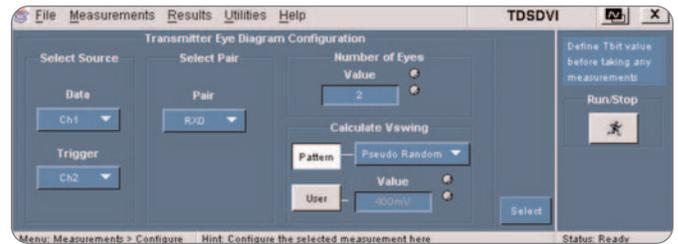
An oscilloscope is the most crucial test instrument for DVI measurements. When selecting an oscilloscope for these measurements it is important to consider the oscilloscope's bandwidth, rise time, and the acquisition technology.

### Bandwidth and Rise-time

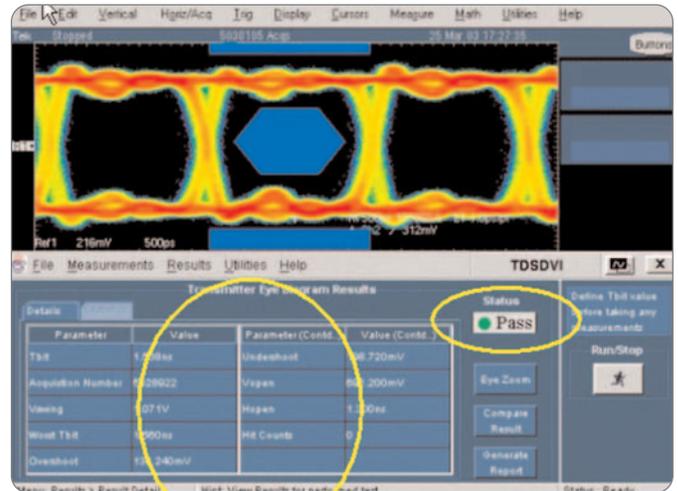
DVI specification defines rise-time from 20% - 80%. This is the rise-time of the differential signal as it transitions from 20% to 80% of its differential amplitude. It is important to make sure that the oscilloscope can handle rise-times of the given order. The required rise-time of the oscilloscope should be at least three times faster than that of the signal rise-time. DVI typically (up to UXGA) encounters rise-times of the order of 250 ps to 300 ps. Hence, an oscilloscope



► Figure 3.



► Figure 4.



► Figure 5.

with a rise-time of about 50 ps to 100 ps is the best tool for DVI conformance testing. The TDS7704B and TDS7404B oscilloscopes offer bandwidths of 7 GHz and 4 GHz with rise times (20% - 80%) of 43 ps and 72 ps, respectively.

## Acquisition Speed

DVI specification for eye testing recommends acquiring a million acquisitions for creating the worst-case jitter condition in the eye diagram. Using a digital storage oscilloscope might take the user about an hour to accumulate one million acquisitions. A Digital Phosphor Oscilloscope (DPO) in FastAcq mode acquires a million acquisitions in less than 10 seconds and hence allows performing compliance testing quickly. TDS7704B, TDS/CSA7404B Digital Phosphor Oscilloscopes offer acquisition speeds up to 400,000 waveforms per second and hence quicken the entire test

## Probes

Since the DVI signals are differential in nature, a differential probe is extremely important. Using pseudo-differential methods of channel subtraction result in unreliable measurements.

The recommended probes for DVI testing are P7350, P7330 or P6330.

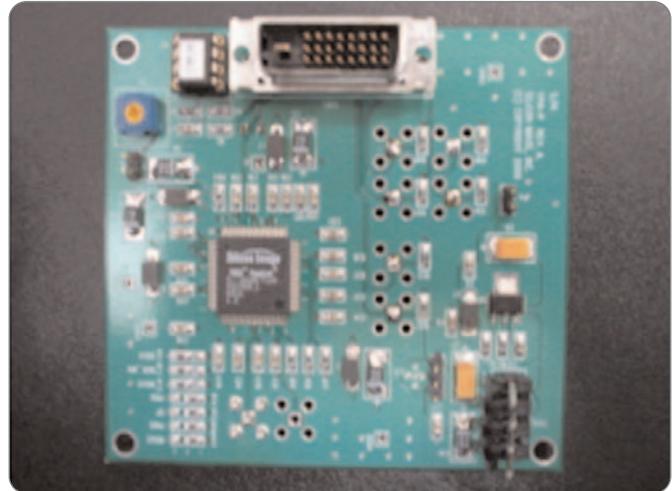
## Test Software

Compliance testing is a challenge if it needs human intervention. Human intervention makes testing difficult and slows the test process. The DVI transmitter eye-masks (TP2) are normalized and change dynamically with the  $V_{swing}$  and  $T_{bit}$  values, while the cable and receiver masks (TP3) are normalized in time and change according to the changes in  $T_{bit}$  value of the signal. Further, a user may have to locate the worst eye opening among the ten data bits. This makes manual testing subjective and error prone.

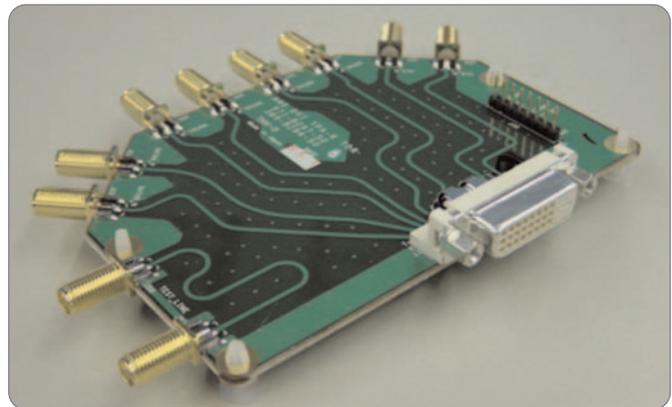
TDSdVI software is the industry's first tool set to enable engineers to perform reliable in-house compliance testing to the DVI specification. It offers a comprehensive range of tests for transmitter, cable and receiver testing for complete standards validation. Automatic "one-button" operation ensures faster testing with higher reliability, in conformance with the DVI Test and Measurement Guide.

## Test Fixtures

The test fixture is a crucial component that enables probing for every test set up. Also, the DVI test and measurement guide recommends recovering the clock (single ended) from the transmitter (differential) clock and use this recovered clock as a trigger source to the oscilloscope for signal integrity testing. The ideal test fixture should provide a PLL (Phased Locked Loop) in accordance to the DVI specifications and also provide access to the differential data lines for probing.



► **Figure 6.** DDWG furnished TPA-P fixture.



► **Figure 7.** DVI TPA-R TDR fixture.

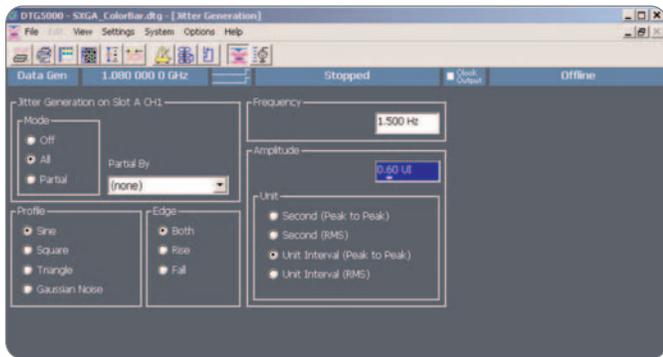
Tektronix fixtures:

DVI TPA-R Test adapter set – 013-A014-50 Includes:

- 2) DVI TPA-R TDR
- 1) DVI TPA– R DI (differential)
- 1) DVI TPA – R SE (single ended)

# Understanding Digital Video Interface (DVI) Compliance Testing

## ► Application Note

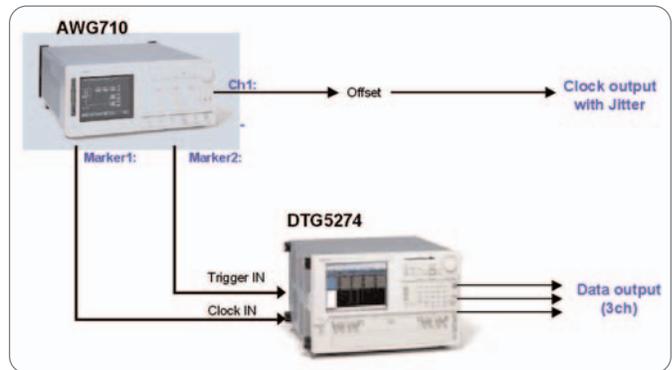


► **Figure 8.** Jitter setup menu in DTG5274.

## Receiver Jitter Tolerance and Receiver Sensitivity Testing

### Jitter Tolerance

One of the most critical characteristics of a receiver is its tolerance to specified levels of jitter in the transmitted clock signals. The DTG5274 can generate jitter on the DVI clock signal for jitter values of less than 1.56MHz without the need for external equipment using a simple setup menu (see Figure 8). To test jitter tolerance at frequencies above 1.56MHz, or to evaluate two elements of jitter frequency, an AWG710 arbitrary waveform generator can be connected to the DTG5274 as shown in Figure 9. The combination provides jitter frequencies greater than 10MHz and multi frequency jitter signals and defined with a simple equation editor Figure 8.



► **Figure 9.** Connecting an arbitrary waveform generator to increase range and variety of jitter.

'Jitter Generation'

clock = 3.7125e9	' Sampling Clock
size = 148500	' Waveform Length
k00_ = 1e6	' Jitter Frequency 1
k01 = 10e6	' Jitter Frequency 2
k1 = 74.25e6	' Clock Frequency
k20 = 500e-12	' Jitter Amplitude 1
k21 = 500e-12	' Jitter Amplitude 2
k3 = 5	' Vertical Scale

"output.wfm" =

$$k3 * \sin(2 * \pi * k1 * (\text{time} + k20/2 * \sin(2 * \pi * k00 * \text{time}) + k21/2 * \sin(2 * \pi * k01 * \text{time})))$$

"output.wfm".marker1 = "marker.wfm".marker1

' Clock for DTG5274

"output.wfm".marker2 = "marker.wfm".marker2

' Trigger for DTG5274

► **Figure 10.** The equation file for AWG710 to generate jitter with two frequency elements.

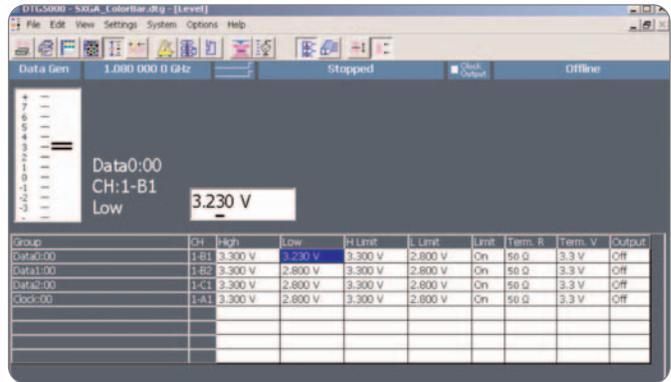
## Receiver Sensitivity

Data signals are varied over a specified range of levels to test the display equipment's ability to tolerate reduced signal voltage. The DTG5274 provides more quantitative and reproducible test results than previous methods that used multiple length cables to attenuate the signals. By providing continuous control of voltage levels in multiple channels, the DTG5274 easily covers all levels within the operating range of the receiver (and beyond) to allow a complete sensitivity analysis. Figure 11 illustrates how easily the sensitivity test signals can be set up in the DTG5274 using its graphic voltage setup menu.

## Conclusion

DVI technology enables higher-end displays to move to digital-interface designs hence improving the performance and video quality. However, this switch from analog transmission to digital transmission presents new challenges that the designer must resolve.

Tektronix offers a comprehensive tool set –sophisticated oscilloscopes, high-speed data time generator, arbitrary waveform generators, differential probes and ingenious test software to enable DVI designers to perform quick, accurate and reliable compliance testing and physical layer validation of their designs. Collectively, this tool set provides superior performance and reliable in-house compliance testing along with unmatched ease-of-use, making it an ideal solution for DVI measurements.



► **Figure 11.** Voltage Level setup menu in DTG5274

## DPO - Digital Phosphor Technology

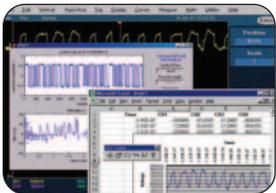
You have to see it to believe it.



A Digital Phosphor Oscilloscope (DPO) is ideal for those who need the best design and troubleshooting tool for a wide range of applications for communication mask testing, digital debug of intermittent signals, repetitive digital design and timing applications. Covering a spectrum of bandwidth from 100 MHz to 7 GHz, Tektronix offers a wide selection of DPOs for you to see a world others don't.

## OpenChoice™

Provides more choices for your networking and analysis solutions.



OpenChoice is a collection of software libraries, utilities, samples, industry-standard protocols and interfaces offered with many Tektronix oscilloscopes and logic analyzers. From 60 MHz to 6 GHz, OpenChoice allows you to communicate with your oscilloscope or logic analyzer over a network, using numerous connectivity protocols and physical interfaces, such as GPIB, Ethernet, RS-232 and shared memory, for you to see a world others don't.

## TekConnect®

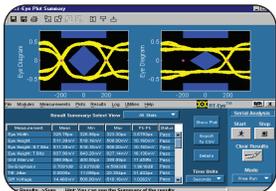
Superior signal fidelity and unparalleled versatility at your fingertips.



TekConnect interface takes probe intelligence to the next level whether you are measuring high voltage, current, power, or even micro-volt level signals. The TekConnect interface ensures superior signal fidelity with useful bandpass up to 18 GHz at the oscilloscope input, while offering unparalleled versatility. With the TekConnect interface, you can be assured that maximum signal integrity is maintained to meet your present and future bandwidth needs.

## Oscilloscope Software

Turn your general purpose oscilloscope into a highly specialized analysis tool.



Tektronix offers exceptional application solutions that instill your oscilloscope with specific technology or procedure expertise, vastly simplifying the development and testing of specialized designs. From serial data standards to power measurements, Tektronix has the broadest selection of oscilloscope software to convert your oscilloscope into a highly specialized and power analysis tool.

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